International Rectifier

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated
- Lead-Free

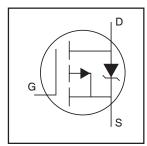
Description

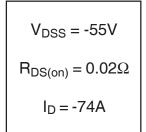
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

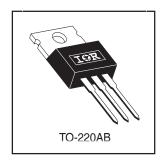
The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

IRF4905PbF

HEXFET® Power MOSFET







Absolute Maximum Ratings

	Parameter	Max.	Units	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ -10V	-74		
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ -10V	-52	A	
I _{DM}	Pulsed Drain Current ①	-260		
$P_{D} @ T_{C} = 25^{\circ}C$	Power Dissipation	200	W	
	Linear Derating Factor	1.3	W/°C	
V _{GS}	Gate-to-Source Voltage	± 20	V	
E _{AS}	Single Pulse Avalanche Energy®	930	mJ	
I _{AR}	Avalanche Current①	-38	A	
E _{AR}	Repetitive Avalanche Energy①	20	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	-5.0	V/ns	
TJ	Operating Junction and	-55 to + 175		
T _{STG}	Storage Temperature Range		∞	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)		

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		0.75	
R _{0CS}	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
R _{eJA}	Junction-to-Ambient		62	

Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	-55			٧	$V_{GS} = 0V, I_D = -250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.05		V/°C	Reference to 25°C, I _D = -1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.02	Ω	V _{GS} = -10V, I _D = -38A ④
V _{GS(th)}	Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS} = V_{GS}$, $I_D = -250\mu A$
9 _{fs}	Forward Transconductance	21			S	$V_{DS} = -25V, I_{D} = -38A$
L	Drain-to-Source Leakage Current			-25	μА	$V_{DS} = -55V, V_{GS} = 0V$
IDSS	Brain to Godice Leakage Guiterit			-250	μΑ	$V_{DS} = -44V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
1	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
I _{GSS}	Gate-to-Source Reverse Leakage			-100	l IIA	V _{GS} = -20V
Qg	Total Gate Charge			180		I _D = -38A
Q _{gs}	Gate-to-Source Charge			32	nC	$V_{DS} = -44V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			86		V_{GS} = -10V, See Fig. 6 and 13 \oplus
t _{d(on)}	Turn-On Delay Time		18			$V_{DD} = -28V$
t _r	RiseTime		99]	$I_{D} = -38A$
t _{d(off)}	Turn-Off Delay Time		61		ns	$R_G = 2.5\Omega$
t _f	FallTime		96			$R_D = 0.72\Omega$, See Fig. 10 \oplus
	Internal Drain Indicators		4.5		nH	Between lead,
L _D	Internal Drain Inductance		4.5			6mm (0.25in.)
L _S	Internal Source Inductance		7.5			from package
						and center of die contact
C _{iss}	Input Capacitance		3400			$V_{GS} = 0V$
C _{oss}	Output Capacitance		1400		рF	$V_{DS} = -25V$
C _{rss}	Reverse Transfer Capacitance		640			f = 1.0MHz, See Fig. 5

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current		-74	4 A	MOSFET symbol	
	(Body Diode)				showing the	
I _{SM}	Pulsed Source Current			000		integral reverse
	(Body Diode) ①		260	260	p-n junction diode.	
V _{SD}	Diode Forward Voltage			-1.6	V	T _J = 25°C, I _S = -38A, V _{GS} = 0V ⊕
t _{rr}	Reverse Recovery Time		89	130	ns	T _J = 25°C, I _F = -38A
Q _{rr}	Reverse Recovery Charge		230	350	nC	di/dt = -100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\begin{tabular}{ll} \hline @ Starting T_J = $25^{\circ}C$, $L = 1.3mH$ \\ R_G = 25Ω, I_{AS} = $-38A$. (See Figure 12) \\ \hline \end{tabular}$
- $\begin{tabular}{l} @ I_{SD} \le -38A, \ di/dt \le -270A/\mu s, \ V_{DD} \le V_{(BR)DSS}, \\ T_J \le 175 ^{\circ}C \end{tabular}$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.

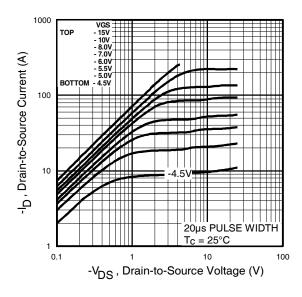


Fig 1. Typical Output Characteristics

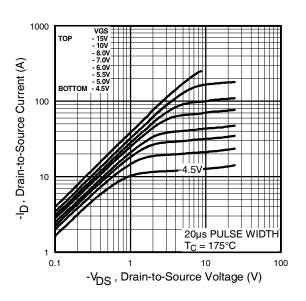


Fig 2. Typical Output Characteristics

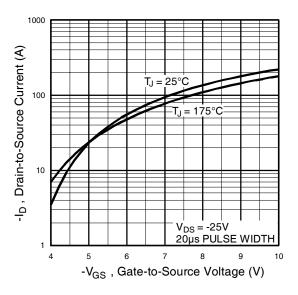


Fig 3. Typical Transfer Characteristics

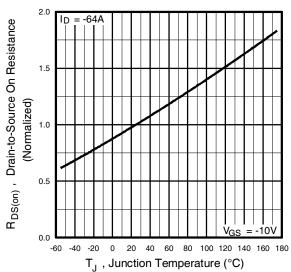


Fig 4. Normalized On-Resistance Vs. Temperature

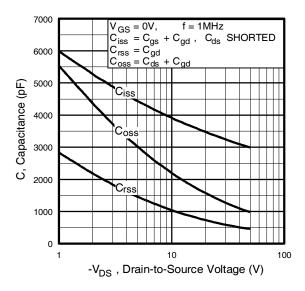


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

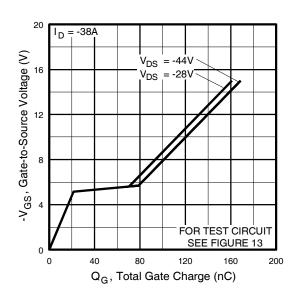


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

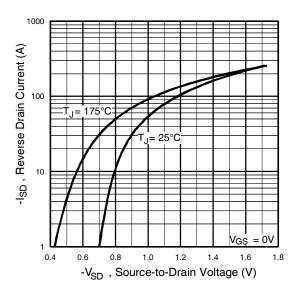


Fig 7. Typical Source-Drain Diode Forward Voltage

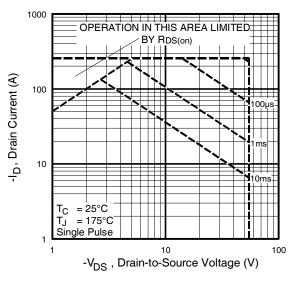


Fig 8. Maximum Safe Operating Area

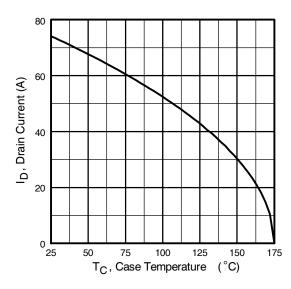


Fig 9. Maximum Drain Current Vs. Case Temperature

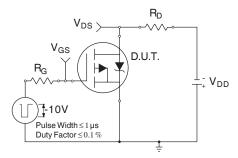


Fig 10a. Switching Time Test Circuit

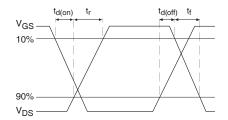


Fig 10b. Switching Time Waveforms

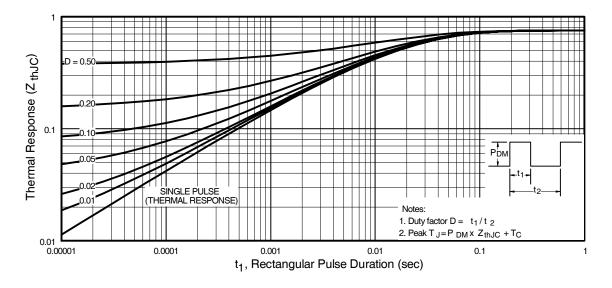


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

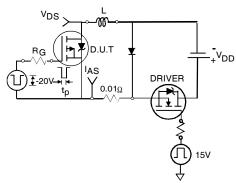


Fig 12a. Unclamped Inductive Test Circuit

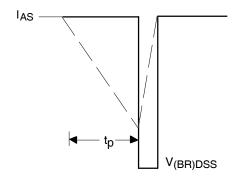


Fig 12b. Unclamped Inductive Waveforms

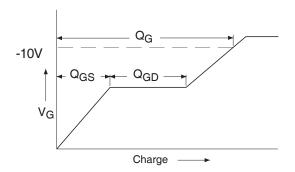


Fig 13a. Basic Gate Charge Waveform

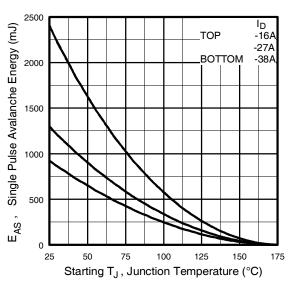


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

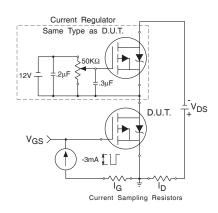
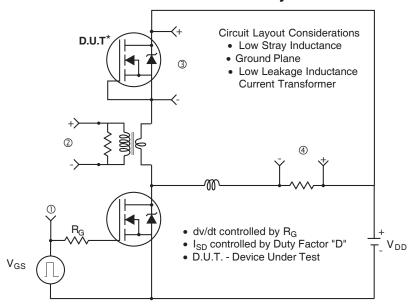
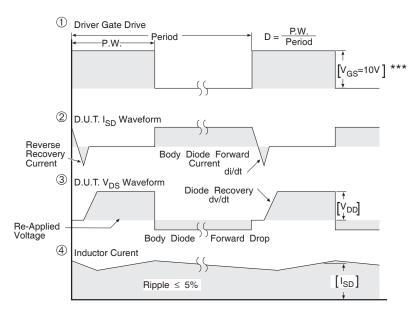


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



^{*} Reverse Polarity of D.U.T for P-Channel

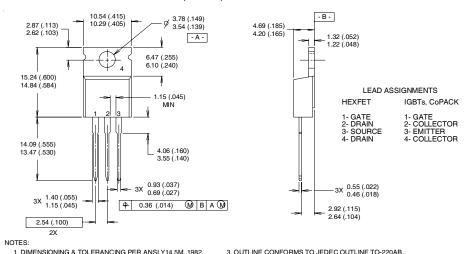


*** $V_{GS} = 5.0V$ for Logic Level and 3V Drive Devices

Fig 14. For P-Channel HEXFETS

TO-220AB Package Outline

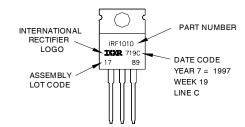
Dimensions are shown in millimeters (inches)



- TO-220AB Part Marking Information
 - EXAMPLE: THIS IS AN IRF1010
 LOT CODE 1789
 ASSEMBLED ON WW 19, 1997
 IN THE ASSEMBLY LINE "C"
 Note: "D" in assembly line

2 CONTROLLING DIMENSION : INCH

Note: "P" in assembly line position indicates "Lead-Free"



4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

Data and specifications subject to change without notice.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105
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Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/

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